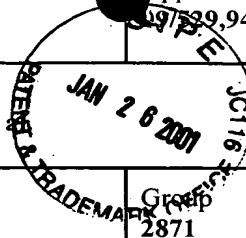


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Date: January 26, 2001Attorney Docket No.  
8733.177.00Application No.  
09/339,948Applicant  
Sergey E. Yakovenko, et al.Filing Date  
April 21, 2000

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EXAMINER INITIAL*		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
①	AA	3,914,022	10/21/75	Kashnow			
①	AB	4,581,608	04/08/86	Aftergut, et al.			
①	AC	4,701,028	10/20/87	Clerc, et al.			
①	AD	4,728,175	03/01/88	Baron			
①	AE	4,786,147	11/22/88	Clerc, et al.			
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①	AI	5,039,185	08/13/91	Uchida, et al.			
①	AJ	5,093,741	03/03/92	Shohara, et al.			

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		Document No.	Date	Country	TRANSLATION	
					YES	NO
①	AK	2 296 810 (A)	07/10/96	Great Britain	X	
①	AL	2 321 718 (A)	08/05/98	Great Britain ✕	X	
①	AM	2 337 843 (A)	12/01/99	Great Britain	X	
①	AN	0 752 611 (A2)	01/08/97	European Patent Office	X	
①	AO	0 814 142 (A2)	12/29/97	European Patent Office	X	
①	AP	0 854 377 (A2)	07/22/98	European Patent Office ✕ *	X	
①	AQ	0 884 626 (A2)	12/16/98	European Patent Office	X	

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①	AR	SID 93 DIGEST, 19.2 "Two-Domain TN-LCDs Fabricated by Parallel Fringe Field Method," by A. Lien and R.A. John, IBM T.J. Watson Research Center, Yorktown Heights, NY., pp. 269-72
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Examiner Signature

Date Considered:

5/30/00

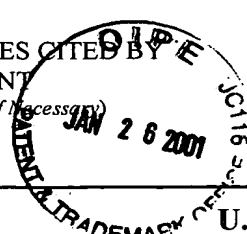
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2871

Date: January 26, 2001



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Q	AA	5,182,664	01/26/93	Clerc			
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Q	AJ	5,608,556	03/04/97	Koma			

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		Document No.	Date	Country	TRANSLATION	
					YES	NO
①	AK	02-294622	12/05/90	JAPAN	ABSTRACT	
②	AL	03-261914	11/21/91	JAPAN ㄱㄷ	ABSTRACT	
③	AM	04-067127	03/03/92	JAPAN	ABSTRACT	
④	AN	04-261522	09/17/92	JAPAN	ABSTRACT	
⑤	AO	05-002161	01/08/93	JAPAN ㄱㄷ	ABSTRACT	
⑥	AP	05-297412	11/12/93	JAPAN	ABSTRACT	
⑦	AQ	06-194656	07/15/94	JAPAN	ABSTRACT	

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①	AA	5,621,558	04/15/97	Shimada, et al.			
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⑩	AJ	5,777,711	07/07/98	Sugiyama			

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		Document No.	Date	Country	TRANSLATION	
					YES	NO
①	AK	06-194657	07/15/94	JAPAN	ABSTRACT	
②	AL	06-258649	09/16/94	JAPAN ✕	ABSTRACT	
③	AM	06-273798	09/30/94	JAPAN ✕ ✕	ABSTRACT	
④	AN	06-281959	10/07/94	JAPAN	ABSTRACT	
⑤	AO	06-301036	10/28/94	JAPAN	ABSTRACT	
⑥	AP	06-347824	12/22/94	JAPAN	ABSTRACT	
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5/30/03

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①	AA	5,249,070	09/28/93	Takano			

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		Document No.	Date	Country	TRANSLATION	
					YES	NO
①	AB	07-013166	01/17/95	JAPAN	ABSTRACT	
①	AC	07-028063	01/31/95	JAPAN	ABSTRACT	
①	AD	07-036044	02/07/95	JAPAN	ABSTRACT	
①	AE	07-043698	02/14/95	JAPAN	ABSTRACT	
①	AF	07-043719	02/14/95	JAPAN	ABSTRACT	
①	AG	07-064089	03/10/95	JAPAN	ABSTRACT	
①	AH	07-181493	07/21/95	JAPAN	ABSTRACT	
①	AI	07-199190	08/04/95	JAPAN	ABSTRACT	
①	AJ	07-230097	08/29/95	JAPAN	ABSTRACT	
①	AK	07-311383	11/28/95	JAPAN	ABSTRACT	
①	AL	08-022023	01/23/96	JAPAN	ABSTRACT	
①	AM	08-076125	03/22/96	JAPAN	ABSTRACT	
①	AN	08-101399	04/16/96	JAPAN	ABSTRACT	
①	AO	08-146468	06/07/96	JAPAN	ABSTRACT	
①	AP	08-220511	08/30/96	JAPAN	ABSTRACT	
①	AQ	08-220524	08/30/96	JAPAN	ABSTRACT	

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①	AR	Euro Display '96, 11.3 "Novel high contrast random and controlled 4-domain CTN-LCDs with wide viewing angle," by H. Murai, M. Suzuki and S. Kaneko, NEC Corp., Kawasaki, Japan, pp. 159-61
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		Document No.	Date	Country	TRANSLATION	
					YES	NO
①	AB	08-313915	11/29/96	JAPAN	ABSTRACT	
①	AC	09-022025	01/21/97	JAPAN	ABSTRACT	
①	AD	09-033890	02/07/97	JAPAN	ABSTRACT	
①	AE	09-152583	06/10/97	JAPAN	ABSTRACT	
①	AF	09-197420	07/31/97	JAPAN	ABSTRACT	
①	AG	09-230360	09/05/97	JAPAN	ABSTRACT	
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①	AI	09-236821	09/09/97	JAPAN	ABSTRACT	
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①	AN	11-109356	04/23/99	JAPAN	ABSTRACT	
①	AO	11-109358	04/23/99	JAPAN	ABSTRACT	
①	AP	11-109362	04/23/99	JAPAN	ABSTRACT	
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①	AR	IDW '97, "A Vertically Aligned LCD Providing Super-High Image Quality," by Y. Koike, S. Kataoka, T. Sasaki, H. Chida, H. Tsuda, A. Takeda and K. Ohmuro, Fujitsu Limited, pp. 159-62
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Examiner Signature

Date Considered:

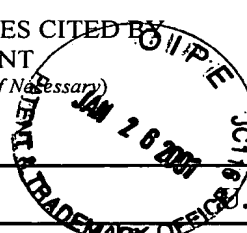
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		Document No.	Date	Country	TRANSLATION	
					YES	NO
①	AB	11-119198	04/30/99	JAPAN	ABSTRACT	
①	AC	11-119209	04/30/99	JAPAN	ABSTRACT	
①	AD	11-148078	06/02/99	JAPAN	ABSTRACT	
①	AE	11-149076	06/02/99	JAPAN	ABSTRACT	
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	AK					
	AL					
	AM					
	AN					

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①	AO	SID 97 DIGEST, P-1 "Development of a High-Quality TFT-LCD for Projection Displays," N. Koma and R. Nishikawa, Sanyo Electric Co., Ltd., Gifu, Japan, pp. 461-4
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